



JPW

Docket No.: 065933-0084

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of	:	Customer Number: 20277
	:	
Ryosuke USUI, et al.	:	Confirmation Number: 3812
	:	
Application No.: 10/813,629	:	Group Art Unit: 2814
	:	
Filed: March 31, 2004	:	Examiner: Dilinh P. Nguyen
	:	
For: SEMICONDUCTOR MODULE AND METHOD OF MANUFACTURING THE SAME		

**CORRECTED INFORMATION DISCLOSURE STATEMENT**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

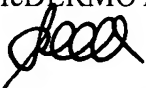
This corrected Information Disclosure Statement is being filed after the filing of the application in order to correct a typographical error in the listing of the Japanese Office Action issued in corresponding Japanese Patent Application No. 2004-086770. **Japanese Patent Application No. 2004-086770** was erroneously listed as **Japanese Patent Application No. 20004-086770** in an Information Disclosure Statement filed on **February 28, 2007**. The reference is correctly listed on the attached form PTO-1449 as Japanese Patent Application No. 2004-086770.

10/813,629

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

McDERMOTT WILL & EMERY LLP



Stephen A. Becker  
Registration No. 26,527

600 13<sup>th</sup> Street, N.W.  
Washington, DC 20005-3096  
Phone: 202.756.8000 SAB:ln  
Facsimile: 202.756.8087  
**Date: March 28, 2007**

**Please recognize our Customer No. 20277  
as our correspondence address.**



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.

065933-0084

SERIAL NO.

10/813,629

APPLICANT

Ryosuke USUI, et al.

FILING DATE

March 31, 2004

GROUP

2814

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
		JP 2001-274293 A	10-05-2001	HITACHI CHEM CO LTD		JAPAN (w/English Abstract)

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Japanese Office Action issued in corresponding Japanese Patent Application No. 2004-086770, dated November 28, 2006

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.

Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.